

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/633,595	<b>Applicant(s)/Patent under Reexamination</b> OIKAWA ET AL.
<b>Examiner</b> Patrick J. Lee	<b>Art Unit</b> 2878	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Files	N/A	6/15/2005	PL